
Optimization of Pin-Fin Heat Sinks Using Entropy Generation Minimization

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- ✓ **Introduction**
- ✓ **Literature Review**
- ✓ **Objectives and Criterion**
- ✓ **Optimization**
- ✓ **Results**
- ✓ **Conclusions**
- ✓ **Acknowledgments**

Introduction

Constraints: L, W, l, w, Q or T_c, T_a and Overall height

Design Variables: D, H, N, U_{app} In-Line/Staggered

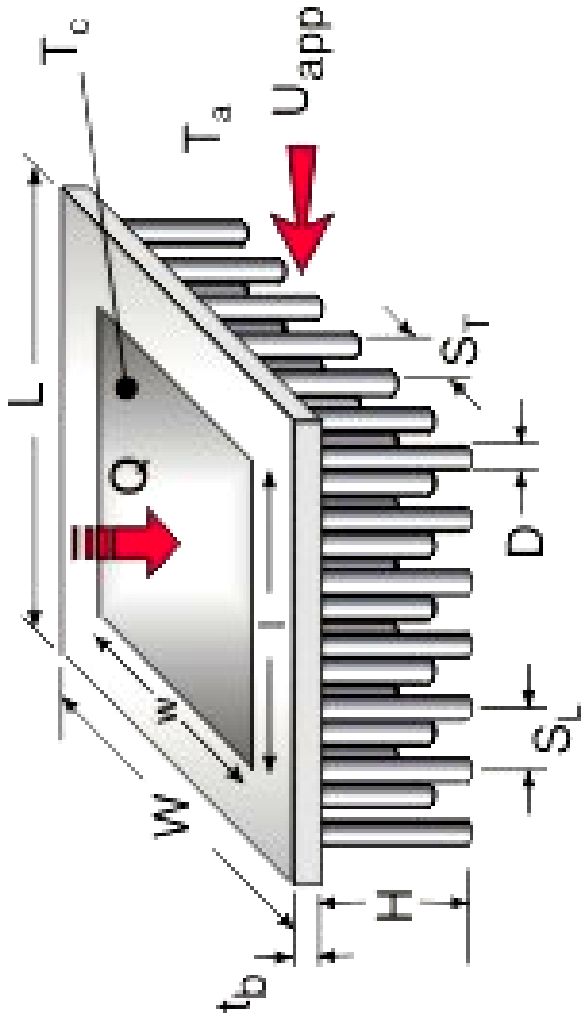
$$40 \leq Re_D \leq 1000$$

$$3 \leq H / D \leq 8$$

$$1.25 \leq S_T / D \leq 3$$

$$1.25 \leq S_L / D \leq 3$$

$$H + t_b \leq 12$$



- ❖ **Theoretical**
- ❖ **Experimental**
- ❖ **No analytical work available to optimize all design variables**

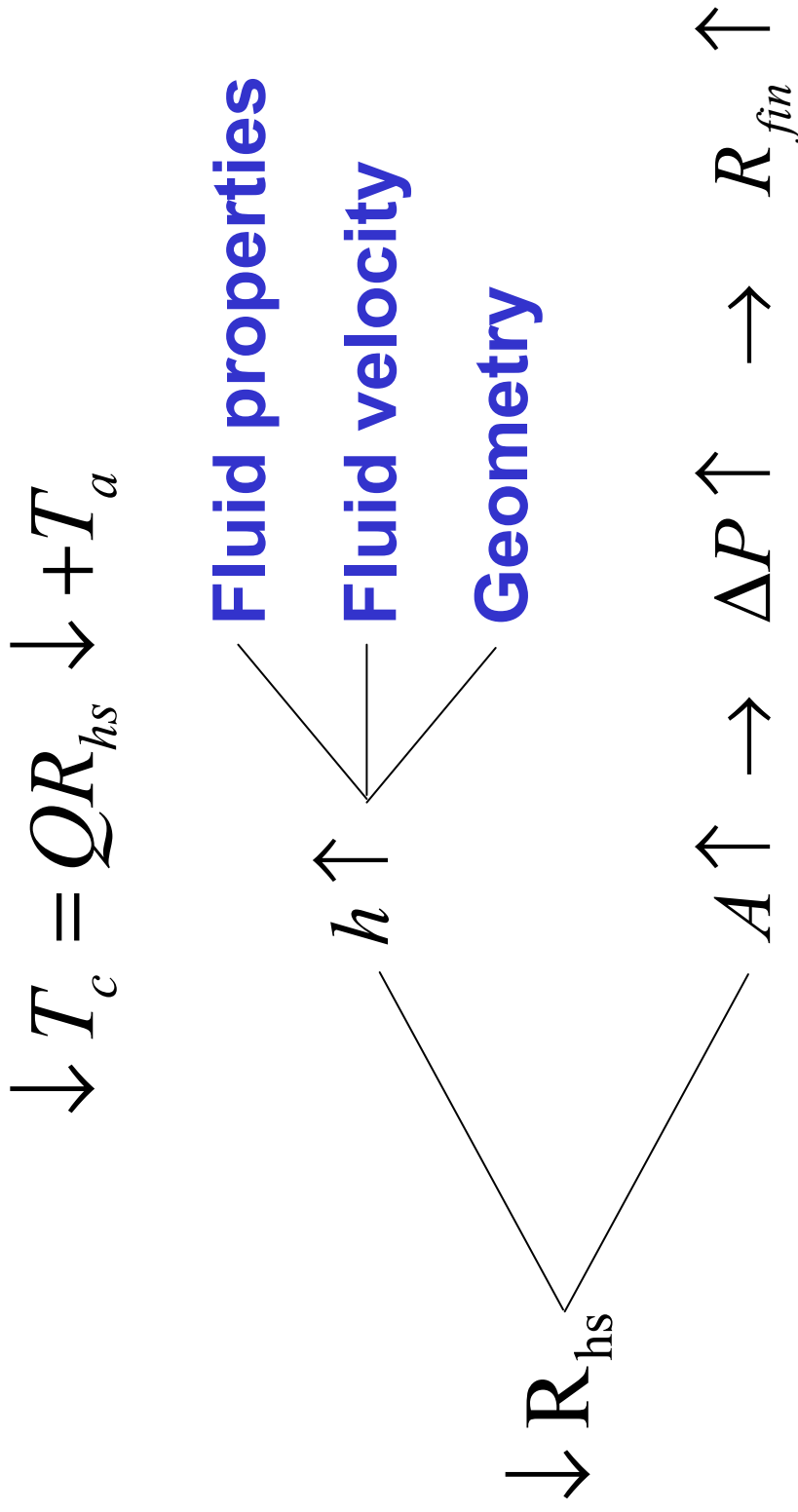
Possible Objective Functions:

- ▶ T_c
- ▶ ΔP
- ▶ Cost
- ▶ Weight

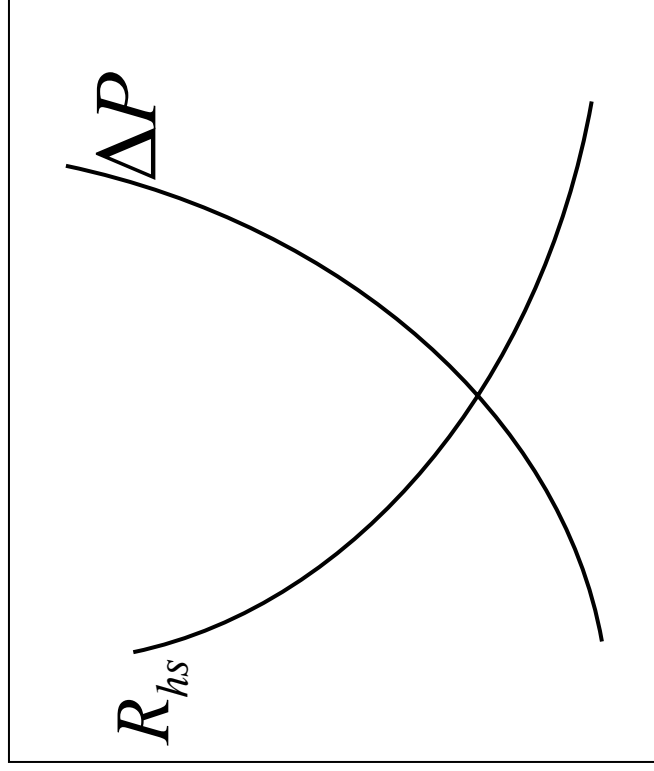
Goal: To Transfer maximum heat, keep chip temperature at minimum

Selected Objective Function:

Minimize T_c

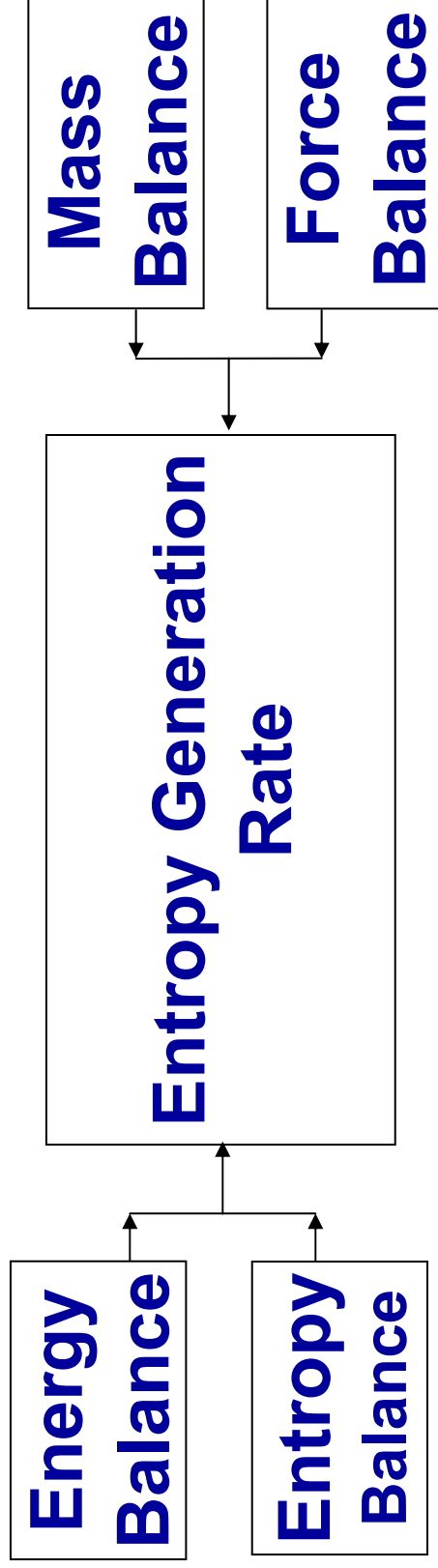


Criterion



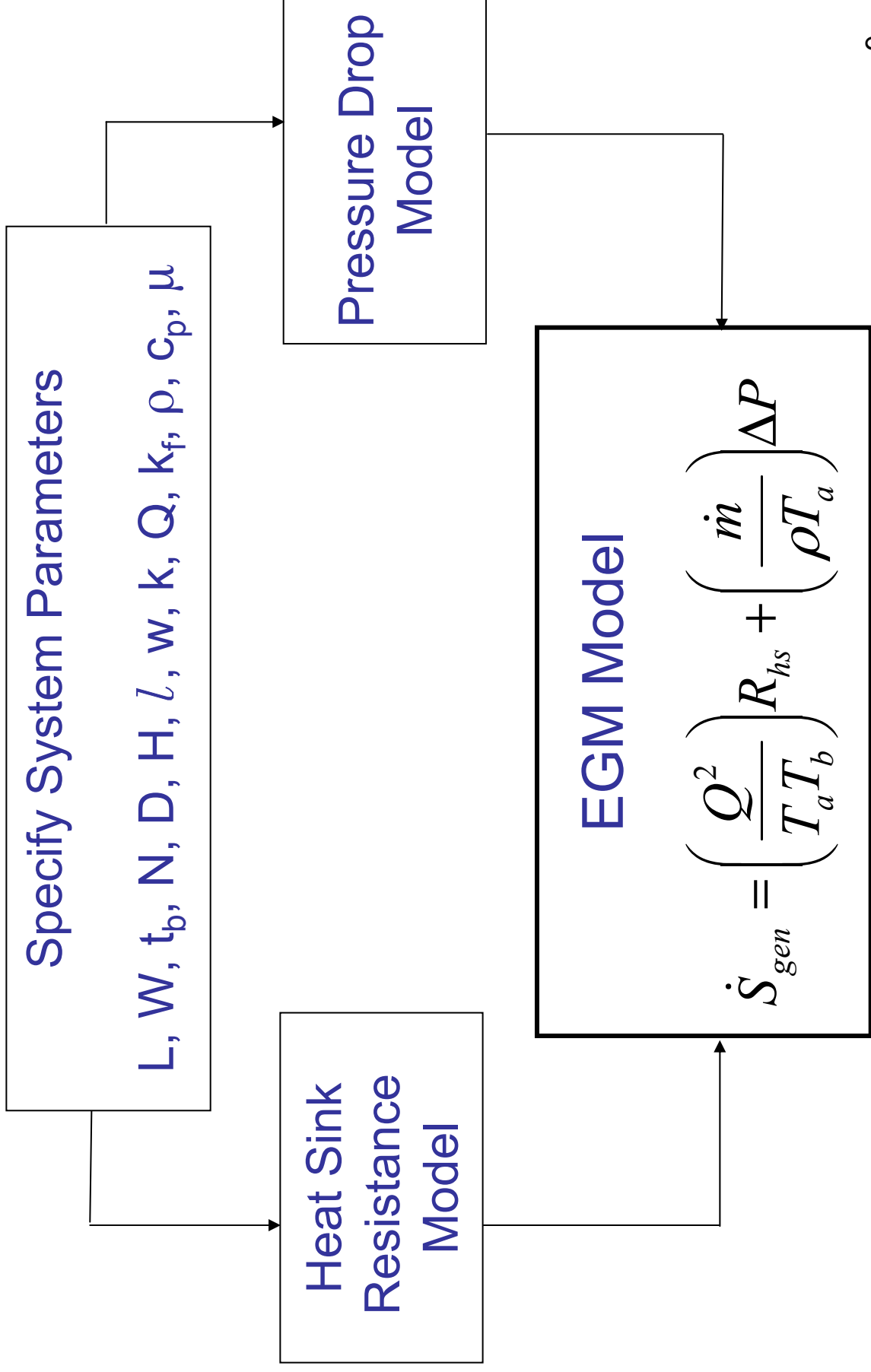
D, N, U_{app}

- **Criterion for rating the performance of heat sinks**
- **Requires thermodynamics, fluid mechanics, heat transfer, material and geometry**

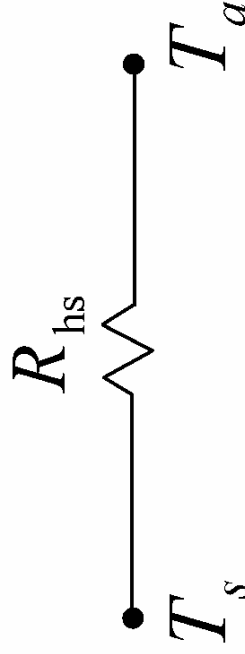
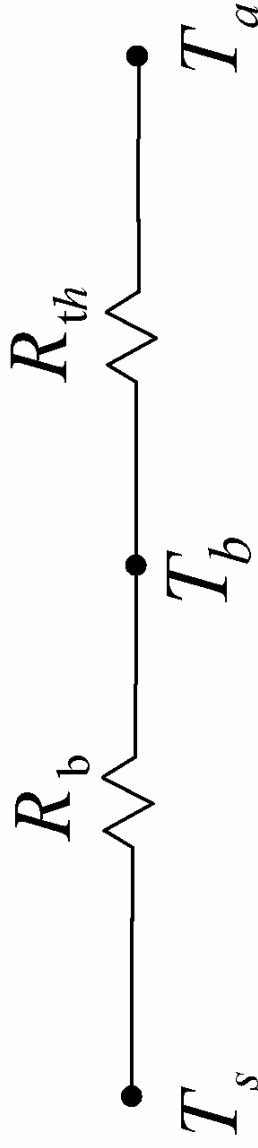
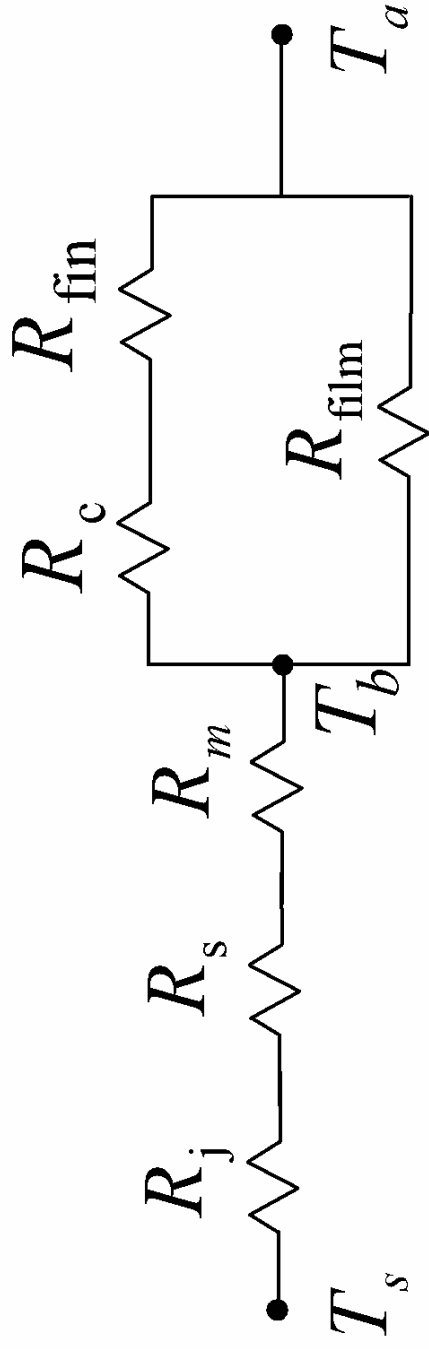


- **Model Development**
- **Problem Formulation**
- **Implementation**

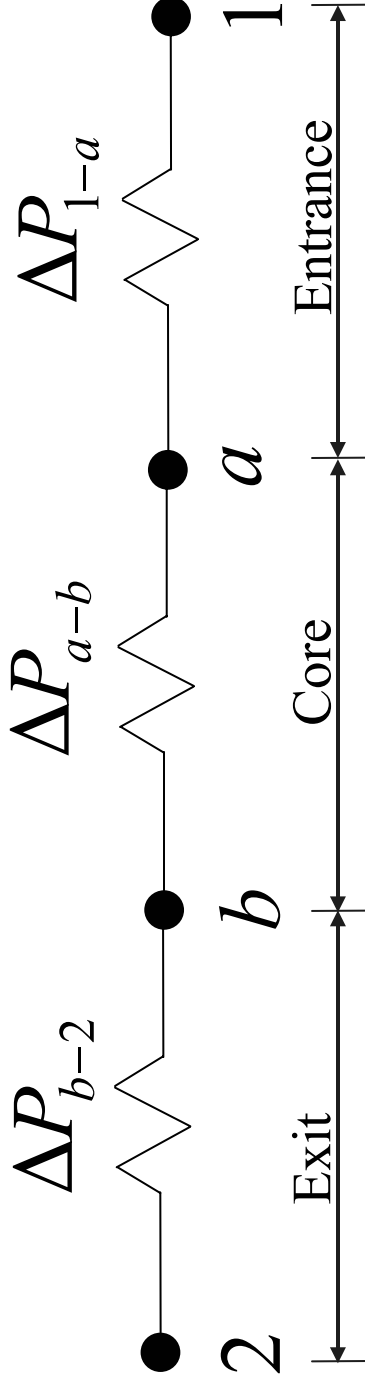
EGM Model



Heat Sink Resistance Model



Pressure Drop Model



$$\Delta P_{1-a} = k_c \cdot \frac{\rho U_{max}^2}{2}$$

$$\Delta P_{b-2} = k_e \cdot \frac{\rho U_{max}^2}{2}$$

$$\Delta P_{a-b} = f N_L \cdot \frac{\rho U_{max}^2}{2}$$

Problem Formulation

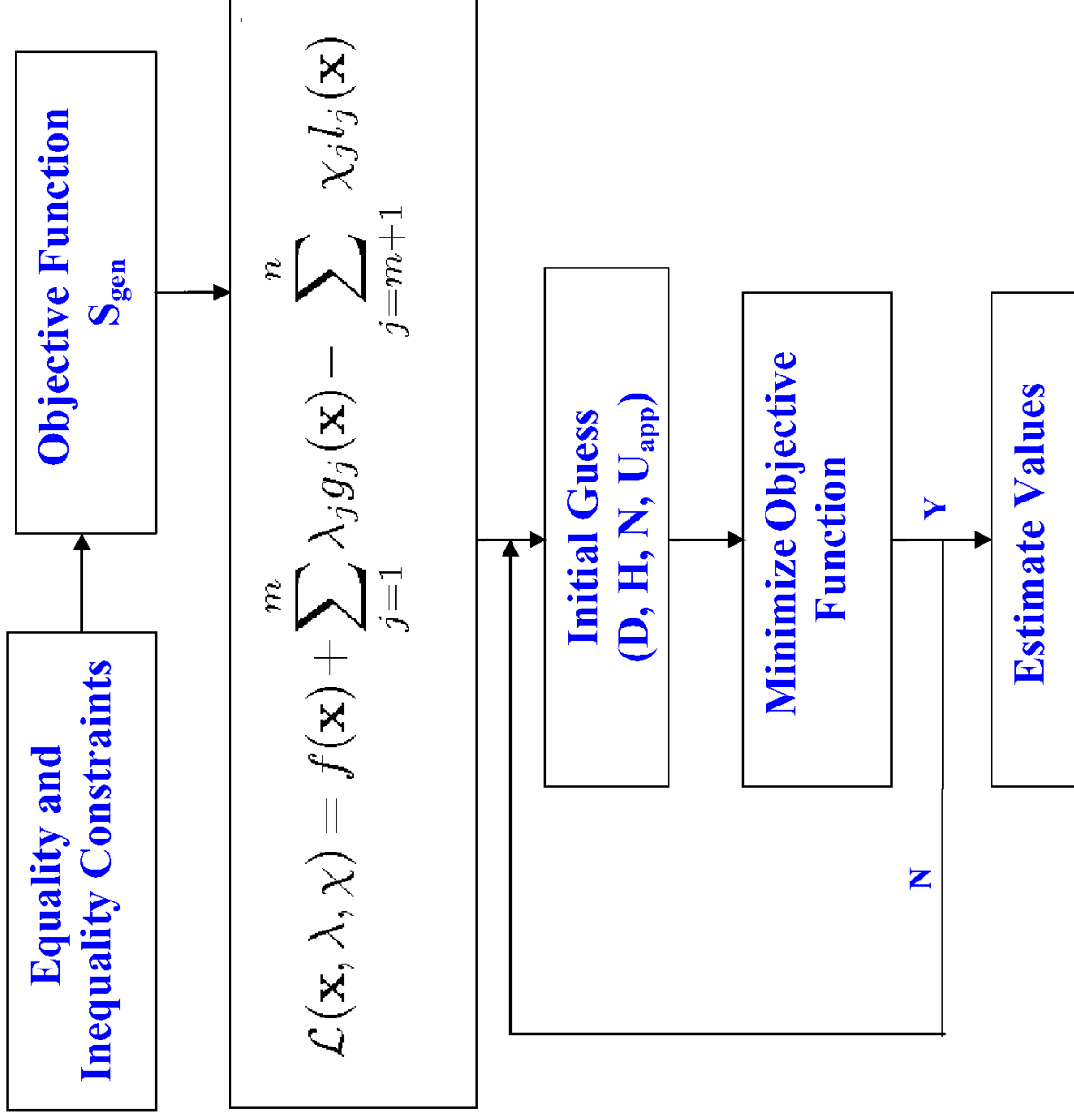
$$\text{minimize } f(\mathbf{x}) = \dot{S}_{\text{gen}}(\mathbf{x})$$

$$g_j(\mathbf{x}) = 0, \quad j = 1, 2, \dots, m$$

$$l_j(\mathbf{x}) \geq 0, \quad j = m + 1, \dots, n$$

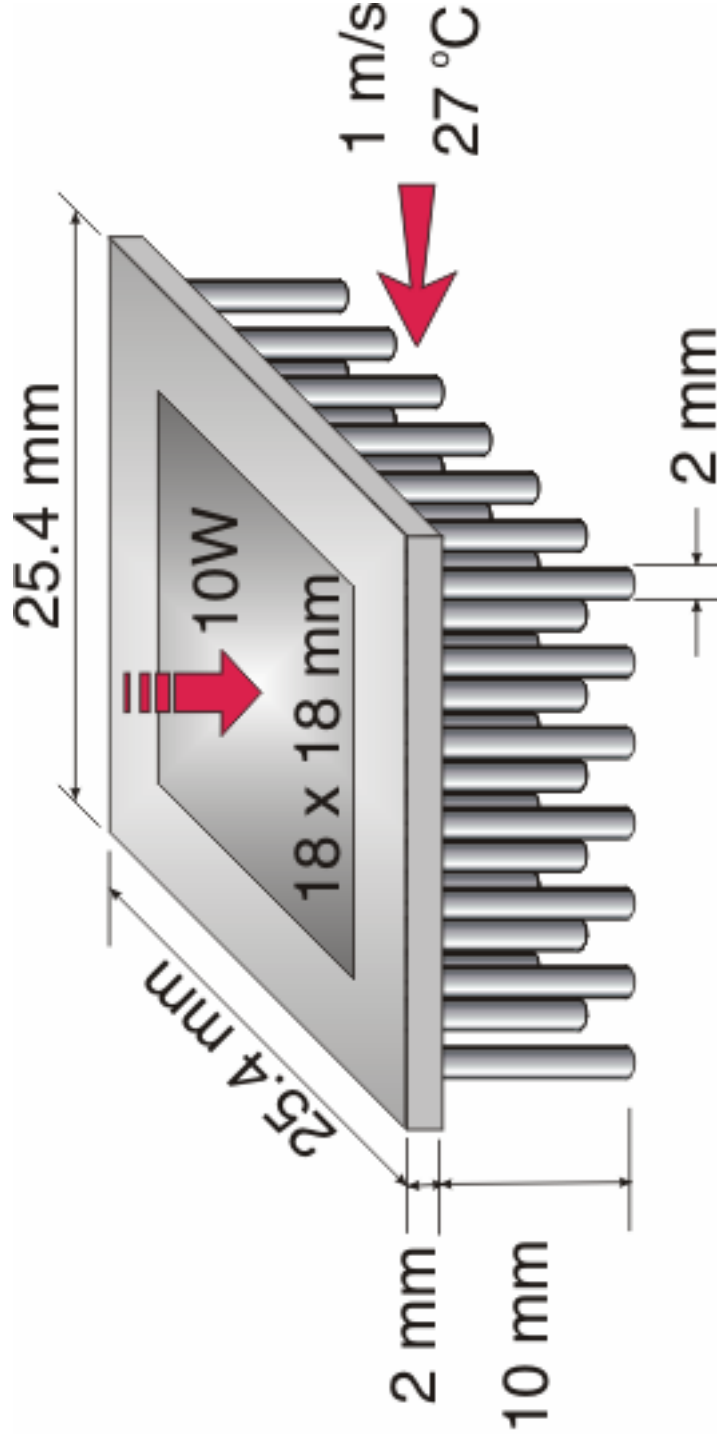
$$\mathcal{L}(\mathbf{x}, \lambda, \chi) = f(\mathbf{x}) + \sum_{j=1}^m \lambda_j g_j(\mathbf{x}) - \sum_{j=m+1}^n \chi_j l_j(\mathbf{x})$$

Implementation

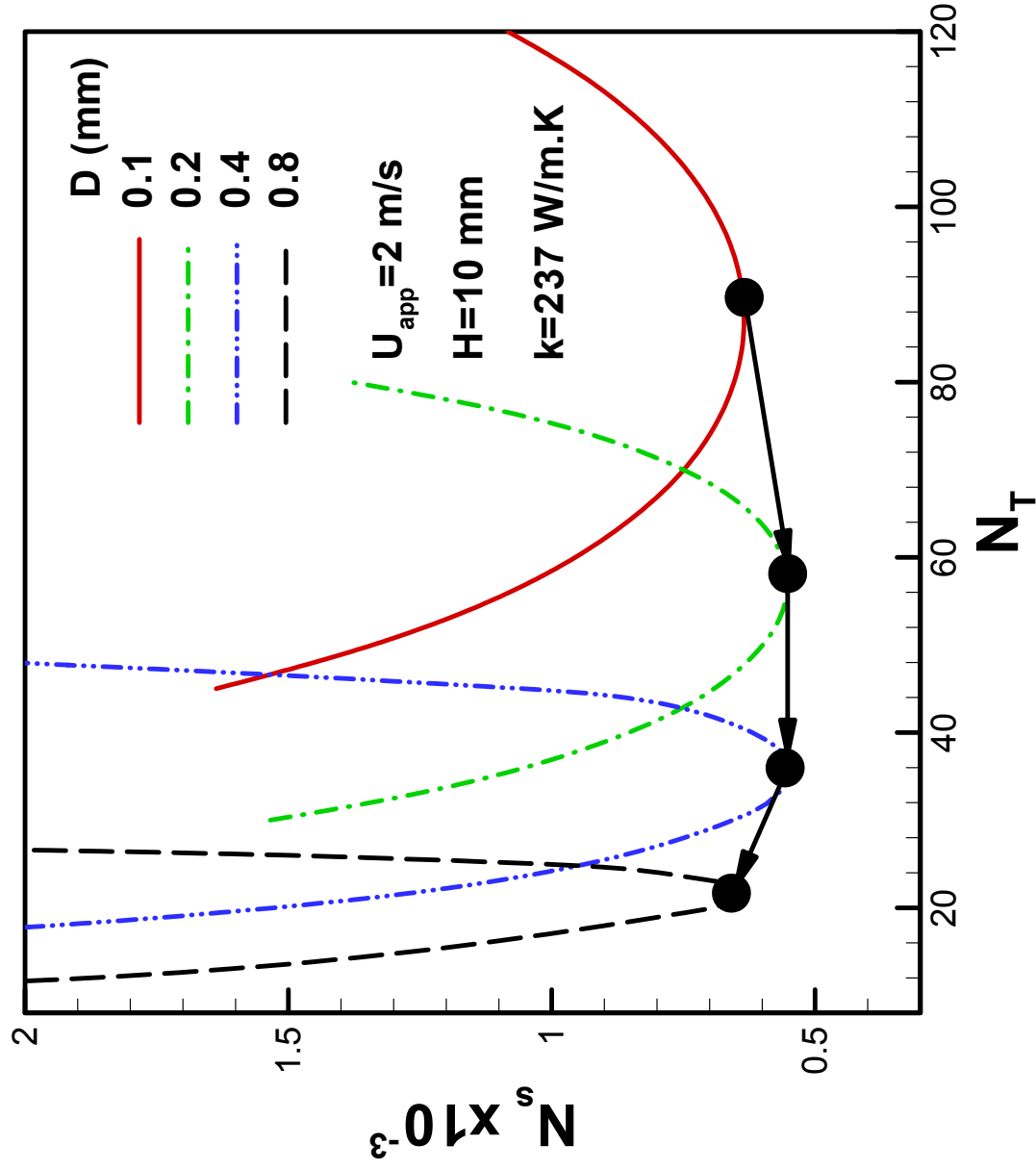


Results

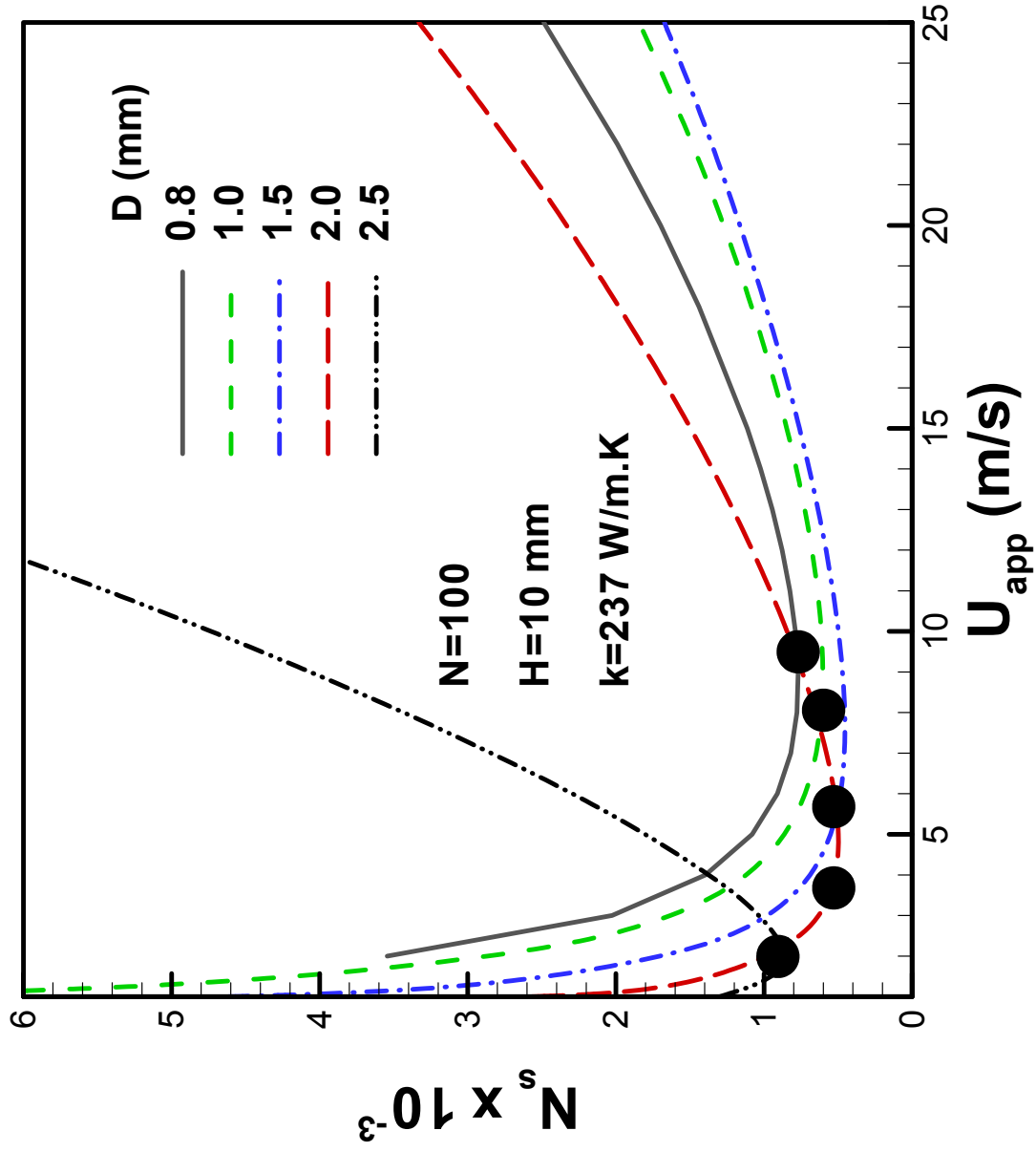
In-Line PFHS



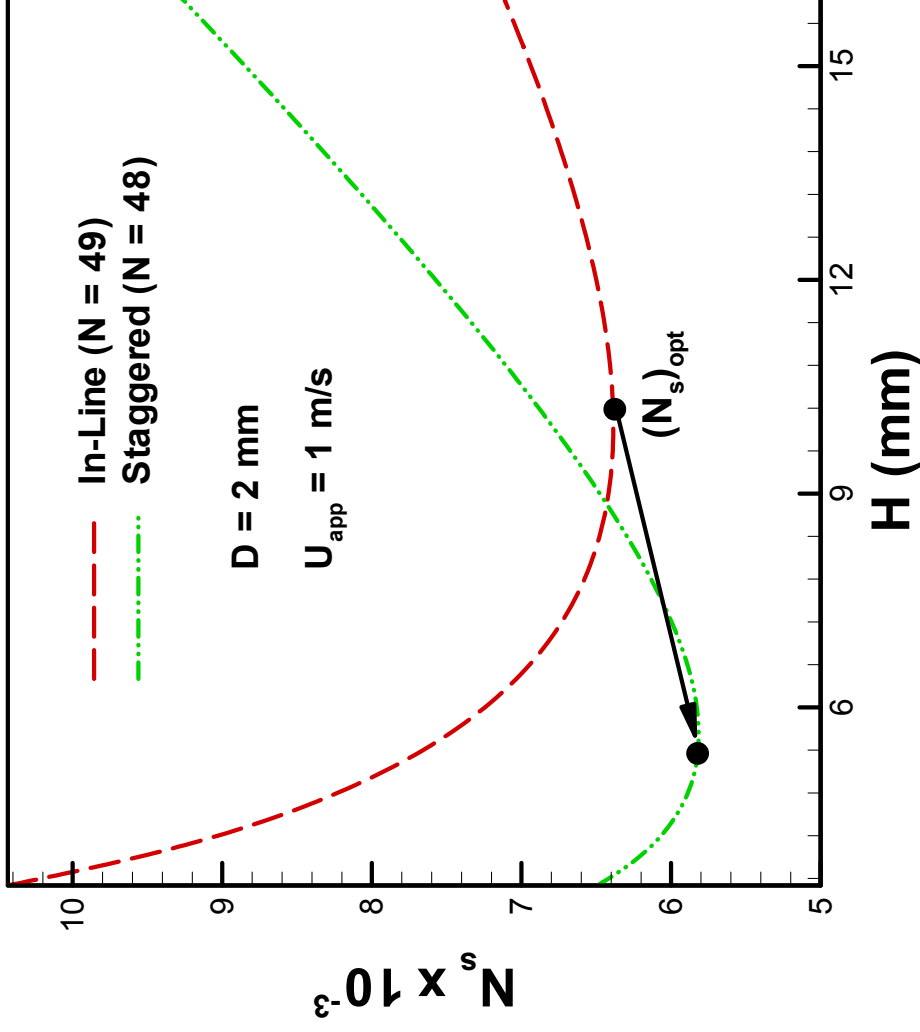
Optimization (In-Line PFHS)



Optimization (In-Line PFHS)



Optimization (Comparison)



Optimization (Four Parameters)

In-Line Arrangement

| k | Optimized Design Variables | | | | R_{hs} | ΔP | \dot{S}_{gen} |
|-----|----------------------------|----------|-----------|------------------|----------|------------|-----------------|
| | D (mm) | H (mm) | U (m/s) | $N_T \times N_L$ | | | |
| 25 | 0.92 | 4 | 4.58 | 11 × 11 | 2.12 | 107.4 | 0.002 |
| 237 | 0.50 | 4 | 3.35 | 18 × 18 | 1.17 | 95.7 | 0.001 |

Staggered Arrangement

| k | Optimized Design Variables | | | | R_{hs} | ΔP | \dot{S}_{gen} |
|-----|----------------------------|----------|-----------|------------------|----------|------------|-----------------|
| | D (mm) | H (mm) | U (m/s) | $N_T \times N_L$ | | | |
| 25 | 0.86 | 4 | 2.29 | 14 × 14 | 1.71 | 175.1 | 0.002 |
| 237 | 0.62 | 4 | 2.00 | 18 × 18 | 1.06 | 168.7 | 0.001 |

- ✓ **EGM is a powerful technique that can**
 - **optimize several parameters**
 - **trade-off between R_{hs} and ΔP**
 - **minimize irreversibility penalty costs**
- ✓ **Possible to design an optimum PFHS**

Acknowledgments

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Optimization Problem

$$\text{minimize } f(\mathbf{x}) = S_{gen}(\mathbf{x})$$

subject to equality constraints

$$L-25.4=0$$

$$W-25.4=0$$

$$l-25.4=0$$

$$w-25.4=0$$

$$T_a-27=0$$

$$Q-10=0$$

and inequality constraints

$$H_{overall} - 12 \leq 0$$

$$S_T/D - 3 \leq 0$$

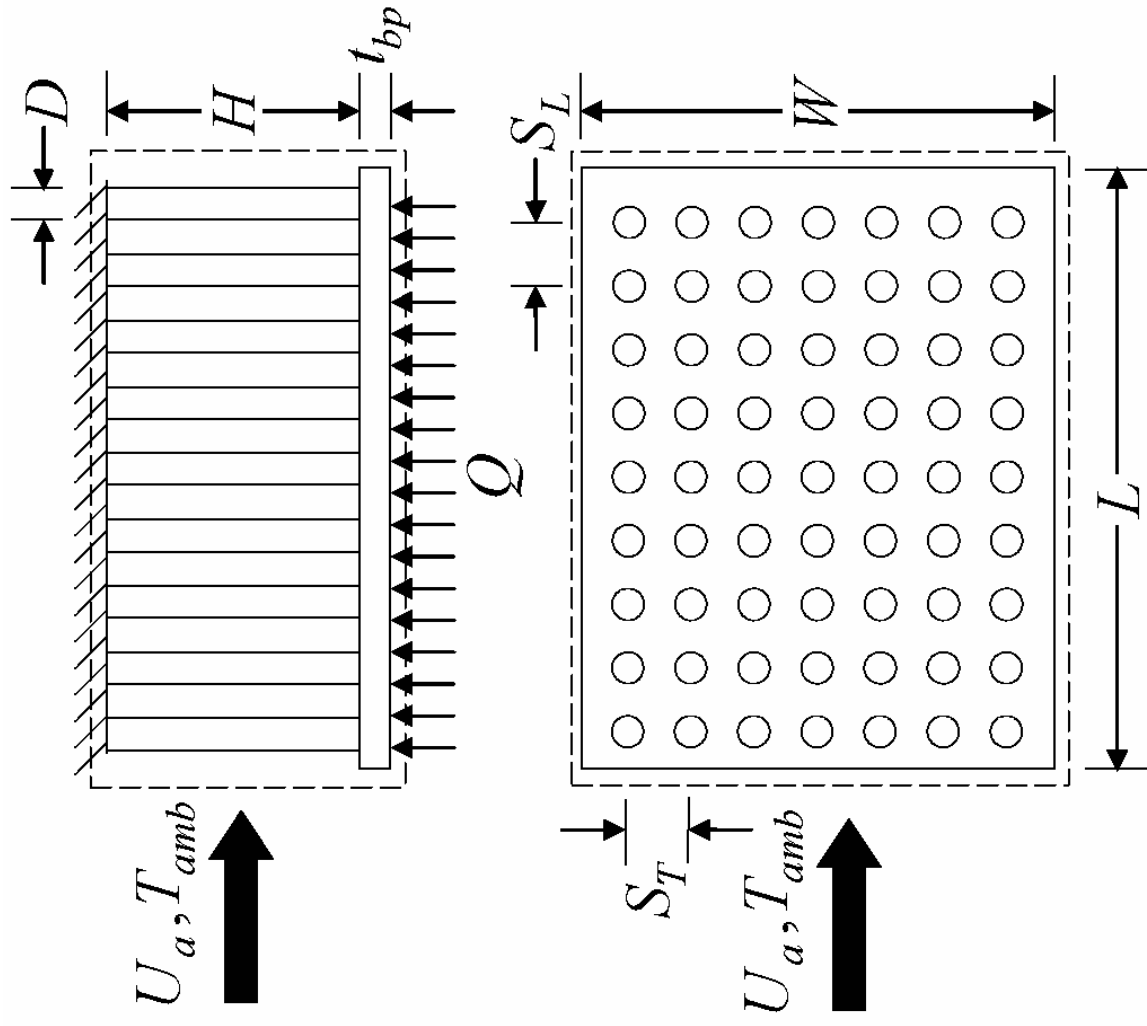
$$S_L/D - 3 \leq 0$$

$$Re_D \leq 1000$$

$$H/D \leq 8$$

$$\mathcal{L}(\mathbf{x}, \lambda, \chi) = f(\mathbf{x}) + \sum_{j=1}^m \lambda_j g_j(\mathbf{x}) - \sum_{j=m+1}^n \chi_j l_j(\mathbf{x})$$

Control Volume



Pin-Fin Arrays

$$\frac{Nu_D}{Re_D^{1/2} Pr^{1/3}} = \begin{cases} \frac{[0.2 + \exp(-0.55S_T)] S_T^{0.785} S_L^{0.212}}{(S_T - 1)^{0.5}} & \text{for In-Line} \\ \frac{0.61 S_T^{0.591} S_L^{0.053}}{(S_T - 1)^{0.5} [1 - 2 \exp(-1.09 S_T)]} & \text{for Staggered} \end{cases}$$

Base Plate

$$\frac{Nu_L}{Re_L^{1/2} Pr^{1/3}} = \begin{cases} 0.750 & \text{for UWT} \\ 0.912 & \text{for UWF} \end{cases}$$

Friction

factors

$$f = \begin{cases} K_1 \left[0.233 + 45.78 / (S_T - 1)^{1.1} Re_D \right] & \text{for In-Line arrays} \\ K_1 \left[378.6 / S_T^{13.1} / S_T \right] / Re_D^{0.68 / S_T^{1.29}} & \text{for Staggered arrays} \end{cases}$$

Correction factors when

$S_T \neq S_L$

$$K_1 = \begin{cases} 1.009 \left(\frac{S_T - 1}{S_L - 1} \right)^{1.09 / Re_D^{0.0553}} & \text{for In-Line arrays} \\ 1.175 (S_L / S_T Re_D^{0.3124}) + 0.5 Re_D^{0.0807} & \text{for Staggered arrays} \end{cases}$$

Contraction coefficient

$$k_c = -0.0311\sigma^2 - .3722\sigma + 1.0676$$

Expansion coefficient

$$k_e = 0.9301\sigma^2 - 2.5746\sigma + 0.973$$

where

$$\sigma = \frac{S_T - 1}{S_T}$$

- Newton – Raphson Method
- Suitable for multiple non-linear equations
- More rapidly convergent
- Sequence of equations listed is immaterial
- Easily adapted in mathematical software packages

Reference Velocity

- For In-Line Pins
$$\frac{U_{\max}}{U_1} = \frac{S_T}{S_T - D}$$

- For Staggered Pins

$$\frac{U_{\max}}{U_1} = \max \left\{ \frac{S_T}{S_T - D}, \frac{S_T}{\sqrt{4S_L^2 + S_T^2} - 2D} \right\}$$

In-Line Arrangement

